

Search Notes 	Application/Control No.	Applicant(s)/Patent under Reexamination
	10/622,149	ROBERDS ET AL.
	Examiner Stephen W. Smoot	Art Unit 2813

S.W.S.

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
Considered all citations from parent application.	3/4/2005	SWS <i>S.W.J.</i>
Key Words: Wafer Thinning - Delamination; Implantation - Cleave, SMARTCUT, ELTRAN, Embrittlement;	3/4/2005	SWS <i>S.W.J.</i>
Polymer - Ether, Arylene, Ketone, Acetylene, Naphthylene, Polyarylene.	3/4/2005	SWS <i>S.W.J.</i>
Search Tools - EAST (attached): USPAT; US PG PUBS; Derwent; EPO; JPO; IBM TDB	3/4/2005	SWS <i>S.W.J.</i>

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner